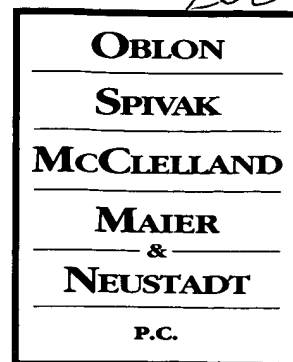




ASSISTANT COMMISSIONER FOR PATENTS
WASHINGTON, D.C. 20231



Re: U.S. Application
Serial No: 09/935,585
Filed: August 24, 2001
Group: 2829
Inventor: Haruo SHINDO, et al.
For: METHOD OF MEASURING
ELECTRON ENERGY
DISTRIBUTION IN
PLASMA REGION AND
APPARATUS FOR
MEASURING THE SAME

ATTORNEYS AT LAW

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SIR:

Attached hereto for filing are the following papers:

PRELIMINARY AMENDMENT w/ Marked-up Copy

Our check in the amount of **\$0.00** is attached covering any required fees. In the event that any variance exists between the amount enclosed and the Patent Office charges for filing the above-noted documents, including any fees required under 37 C.F.R. 1.136 for any necessary Extension of Time to make the filing of the attached documents timely, please charge or credit our Deposit Account No. 15-0030. Further, if these papers are not considered timely filed, then a petition is hereby made under 37 C.F.R. 1.136 for the necessary extension of time. A duplicate copy of this sheet is attached.

Respectfully submitted,

OBLON, SPIVAK, McCLELLAND,
MAIER & NEUSTADT, P.C.

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IN THE UNITED STATES PATENT & TRADEMARK OFFICE

IN RE APPLICATION OF :
Haruo SHINDO ET AL : EXAMINER: PATEL, P.
SERIAL NO: 09/935,585 :
FILED: AUGUST 24, 2001 : GROUP ART UNIT: 2829
FOR: METHOD OF MEASURING :
ELECTRON ENERGY
DISTRIBUTION IN PLASMA
REGION AND APPARATUS
FOR MEASURING THE SAME

PRELIMINARY AMENDMENT

ASSISTANT COMMISSIONER FOR PATENTS
WASHINGTON, D.C. 20231

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SIR:

Prior to an Official Action on the merits, please amend this application as follows:

IN THE CLAIMS

Please add new Claims 10-13 as follows:

10. (New) A measuring apparatus according to claim 4, further comprising:
an A/D converting section which is provided on a same substrate along with the
detecting section or on another substrate and which converts data obtained in the detecting
section to digital data;
a first signal converting section which has a function of converting an electric signal
to an optical signal and vice versa and a function of performing communication and which

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